

OTT Supplemental Material

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Confidential

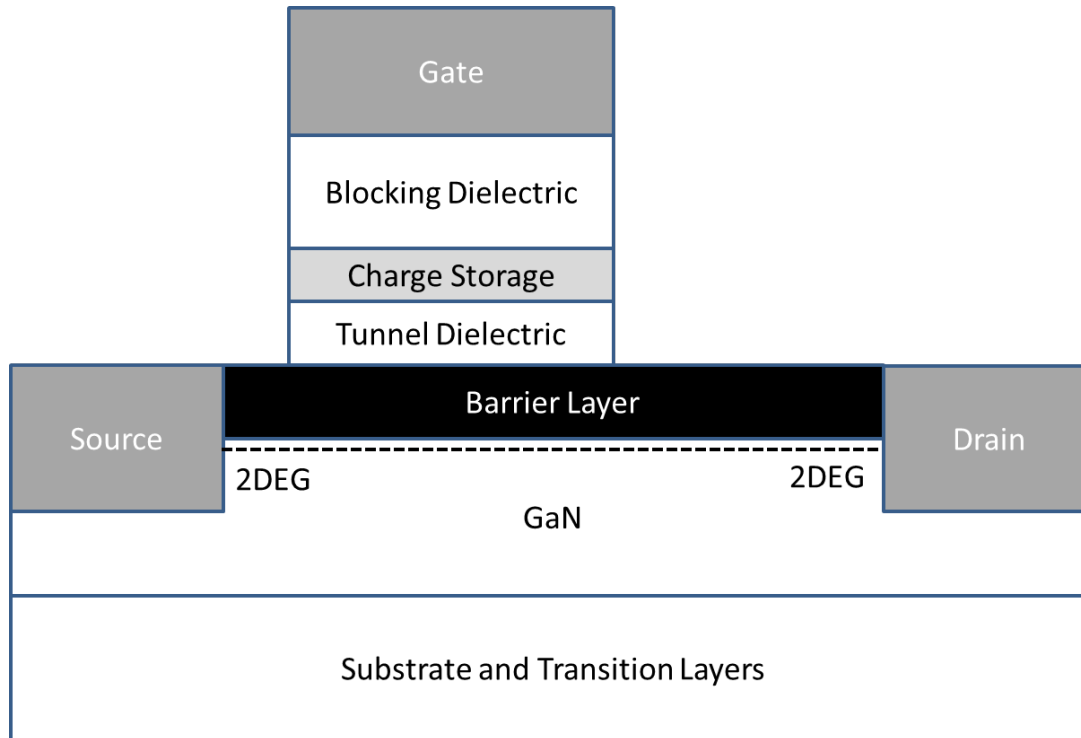


Figure 1. Generalized Flash MOS-HFET Structure

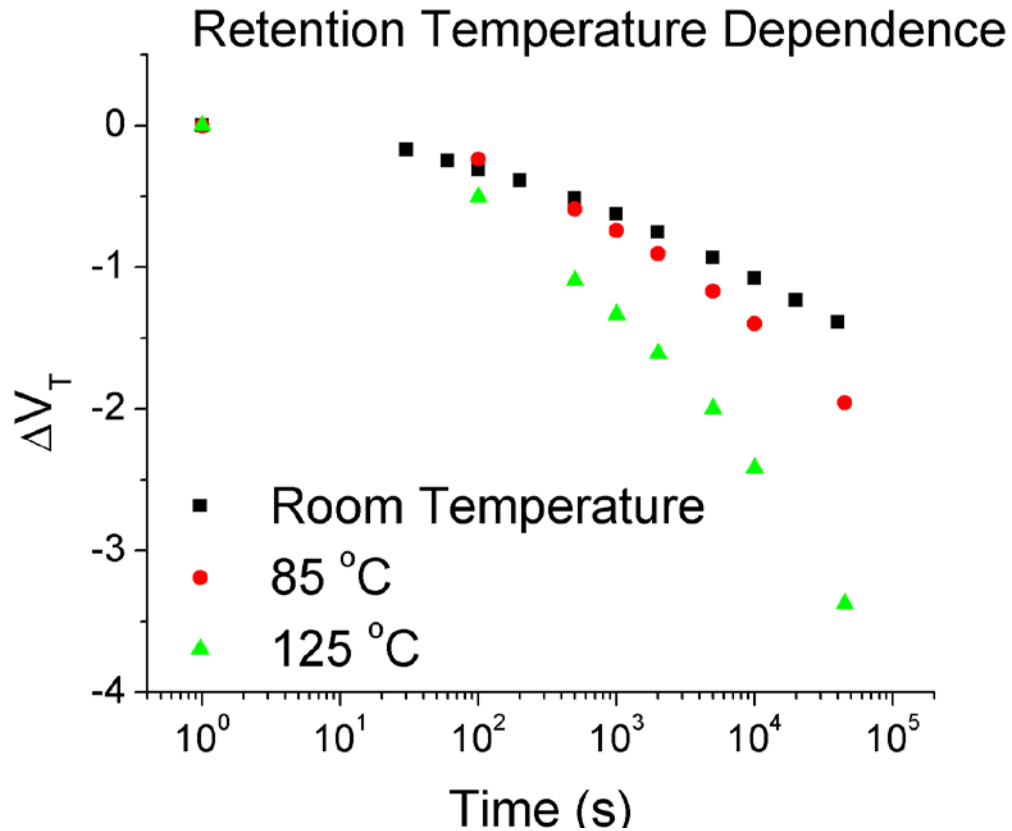


Figure 2. Threshold voltage shift as a function of time for the Flash MOS-HFET with all terminals at 0 bias

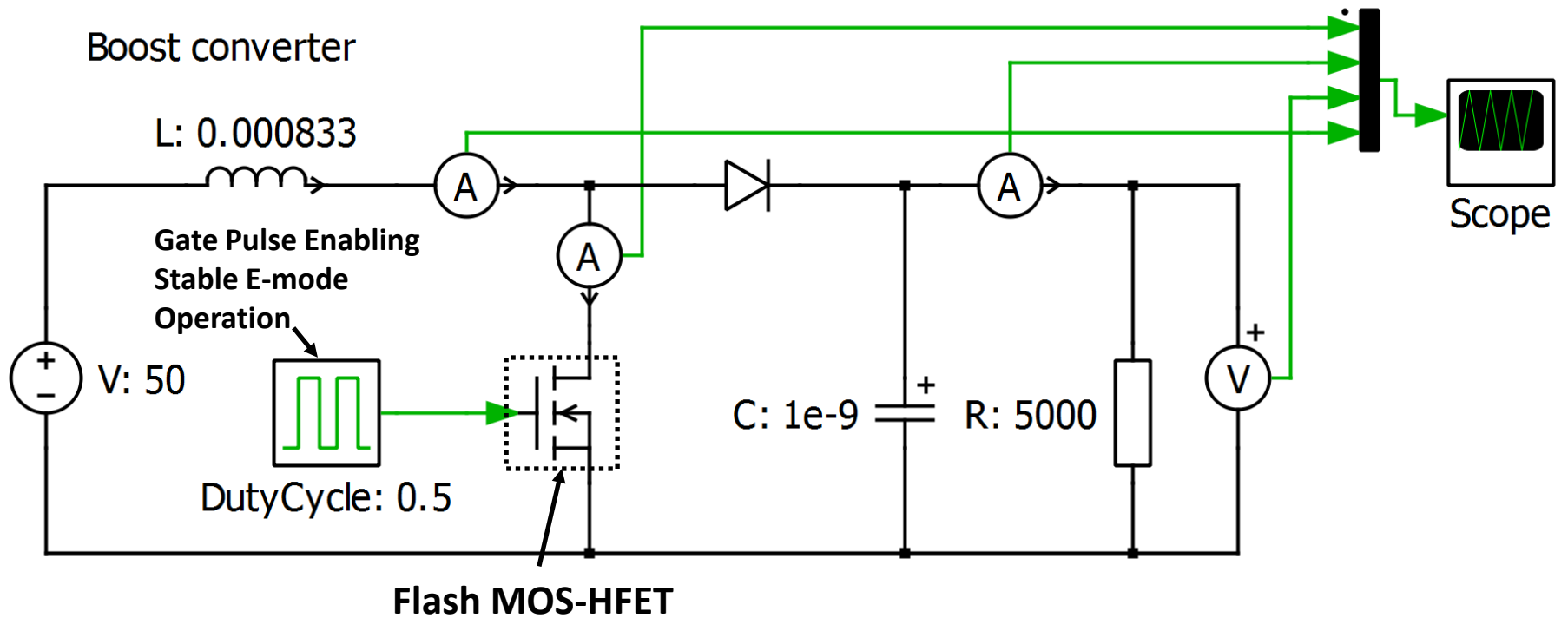


Figure 3. Boost converter circuit designed for stable operation of the Flash MOS-HFET

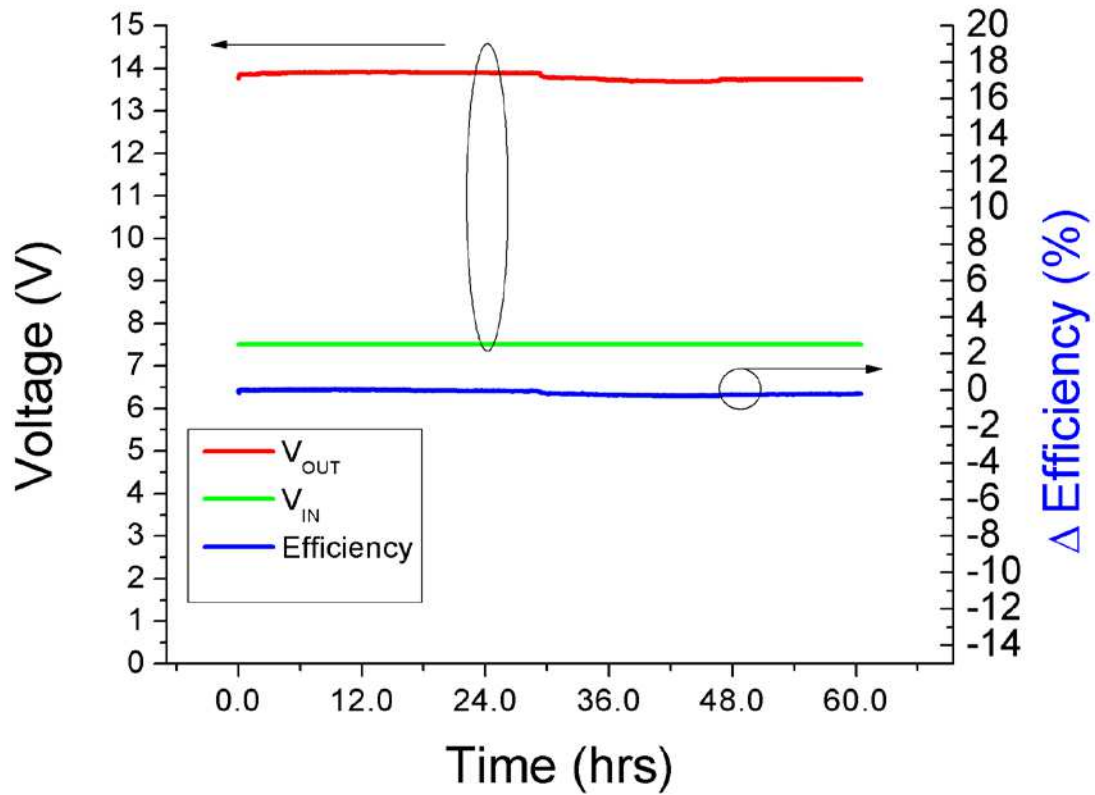


Figure 4. Boost converter output as a function of time showing stable operation and efficiency of the boost converter

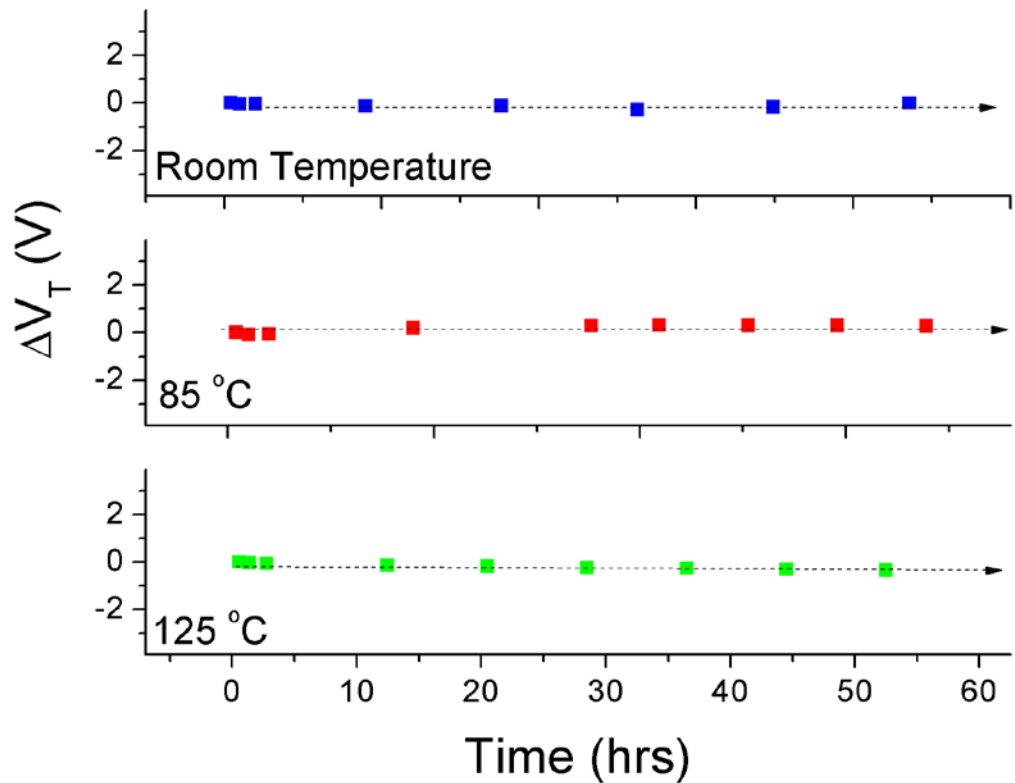


Figure 5. Flash MOS-HFET threshold voltage as a function of time during boost converter operation at several temperatures. Threshold voltage remains constant and positive for the duration of the measurement and extrapolated for the lifetime of the device